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Correction: Compositional effect on the fabrication of $\text{Ag}_x\text{Pd}_{1-x}$ alloy nanoparticles on c-plane sapphire at distinctive stages of the solid-state-dewetting of bimetallic thin films

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 Correction for 'Compositional effect on the fabrication of $\text{Ag}_x\text{Pd}_{1-x}$ alloy nanoparticles on c-plane sapphire at distinctive stages of the solid-state-dewetting of bimetallic thin films' by Puran Pandey *et al.*, *RSC Adv.*, 2017, 7, 55471–55481.

Errors were present in the published article and ESI. The errors in the article are in the plots of SAR and coverage in Fig. 6(m) and (n) and the corrected figure is shown below. At the same time, Fig. 6(l) has been edited in order to be consistent with Fig. 6(m) and (n). Specifically, the blue lines denote " $\text{Pd}_{0.25}\text{Ag}_{0.75}$ " and the black lines " $\text{Pd}_{0.75}\text{Ag}_{0.25}$ ". In the ESI summarized values of R_q in Table S7 were incorrect and the ESI document is now replaced.

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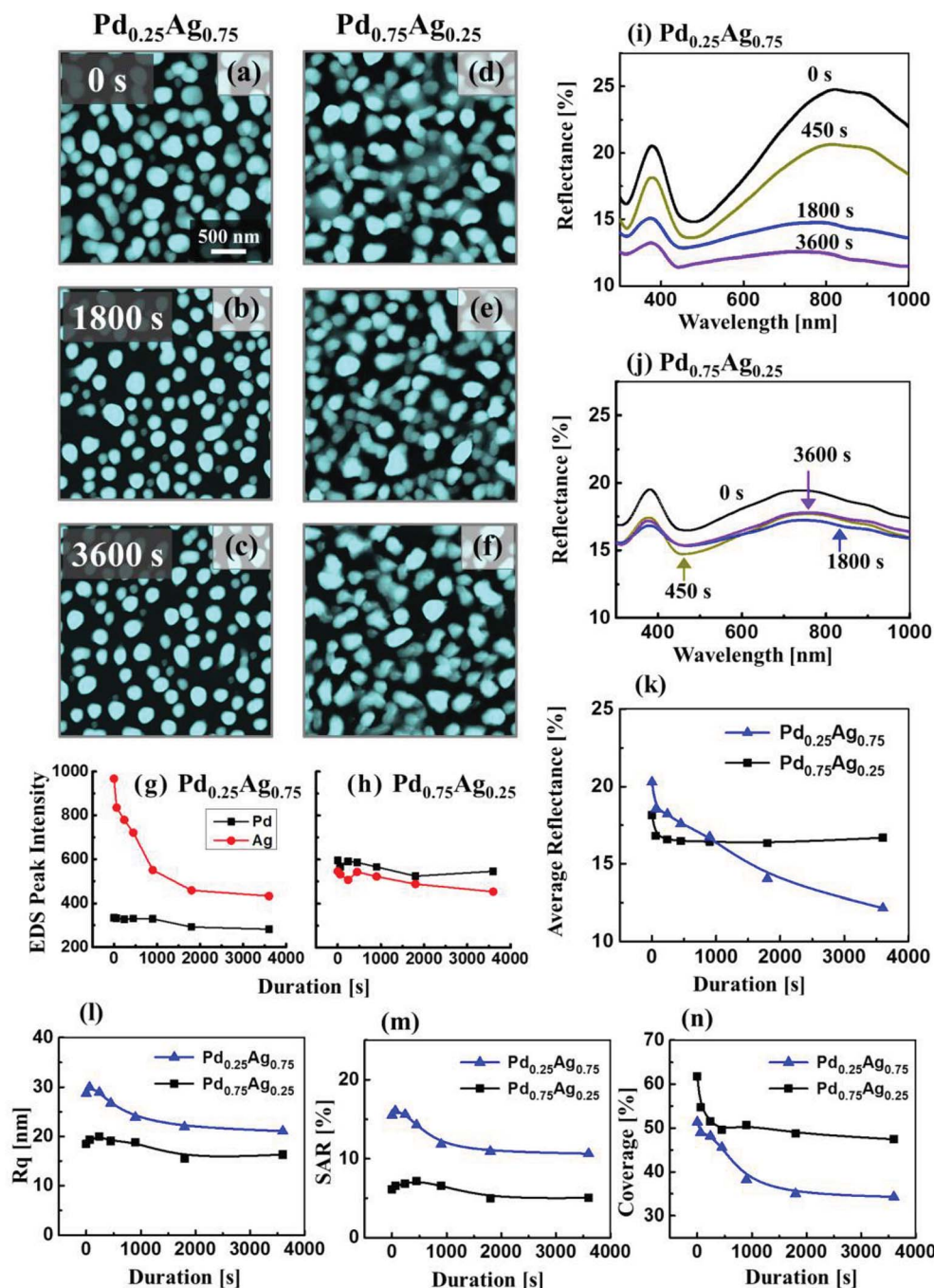



Fig. 6 Evolution of Ag-Pd bimetallic nanostructures by the variation of annealing durations between 0 and 3600 s at 650 °C with the deposition thickness of 10 nm and distinct bilayer composition as labelled. (a)–(f) AFM top-views of $3 \times 3 \mu\text{m}^2$. (g) and (h) Summary of EDS intensities of Ag $\text{L}\alpha_1$ and Pd $\text{L}\alpha_1$ with respect to the annealing durations. (i) and (j) Reflectance spectra of Ag-Pd nanostructures. (k) Summary plot of average reflectance. (l)–(n) Summary plot of R_q , SAR and coverage plots with respect to the annealing duration.

The Royal Society of Chemistry apologises for these errors and any consequent inconvenience to authors and readers.